February 2004



FDS4070N3 40V N-Channel PowerTrench[®] MOSFET

General Description

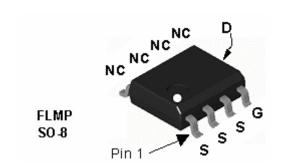
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for "low side" synchronous rectifier operation, providing an extremely low $R_{DS(ON)}$ in a small package.

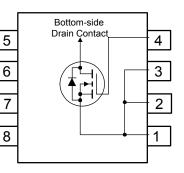
Applications

- Synchronous rectifier
- DC/DC converter

Features

- 15.3 A, 40 V. $R_{\text{DS(ON)}}$ = 7.5 m Ω @ V_{GS} = 10 V
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- High power and current handling capability
- Fast switching, low gate charge
- FLMP SO-8 package: Enhanced thermal performance in industry-standard package size





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		40	V
V _{GSS}	Gate-Source Voltage		± 20	V
ID	Drain Current – Continuous	(Note 1a)	15.3	А
	– Pulsed		60	
P _D	Maximum Power Dissipation	(Note 1a)	3.0	W
T _J , T _{stg}	Operating and Storage Junction Temp	perature Range	–55 to +150	°C

R _{0JA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	0.5	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS4070N3	FDS4070N3	13"	12mm	2500 units

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	ource Avalanche Ratings (Note	2)	•			
E _{AS}	Drain-Source Avalanche Energy	Single Pulse, V_{DD} =40V, I_D =15.3A			310	mJ
I _{AS}	Drain-Source Avalanche Current				15.3	А
Off Char	acteristics					
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 V$, $I_{D} = 250 \mu A$	40			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25°C		42		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 32 V$, $V_{GS} = 0 V$			1	μA
I _{GSSF}	Gate–Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate–Body Leakage, Reverse	$V_{GS} = -20 V, V_{DS} = 0 V$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	2	3.9	5	V
$\Delta V_{GS(th)} \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25 °C		-8		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	V _{GS} = 10 V, I _D = 15.3 A V _{GS} = 10 V, I _D =15.3A, T _J =125°C		5.5 8	7.5 12	mΩ
g fs	Forward Transconductance	V _{DS} = 10 V, I _D = 15.3 A		52		S
Dynamic	c Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 20 V$, $V_{GS} = 0 V$,		2819		pF
Coss	Output Capacitance	f = 1.0 MHz		600		pF
C _{rss}	Reverse Transfer Capacitance			291		pF
Switchin	g Characteristics (Note 2)	•				
t _{d(on)}	Turn–On Delay Time	$V_{DD} = 20 V, I_D = 1 A,$	l –	16	29	ns
t _r	Turn–On Rise Time	V_{GS} = 10 V, R_{GEN} = 6 Ω		12	22	ns
t _{d(off)}	Turn–Off Delay Time	-		41	66	ns
t _f	Turn–Off Fall Time	-		29	46	ns
Q _g	Total Gate Charge	$V_{DS} = 20 V$, $I_D = 15.3 A$,		47	67	nC
Q _{gs}	Gate–Source Charge	V _{GS} = 10 V		15		nC
Q _{gd}	Gate-Drain Charge			14		nC

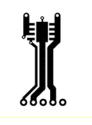
		A	1			1
Symbol	Parameter Test Conditions		Min	Тур	Max	Units
Drain-S	ource Diode Characteristics a	nd Maximum Ratings				
ls	Maximum Continuous Drain–Source Diode Forward Current				2.5	А
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$, $I_S = 2.5 A$ (Note 2)		0.7	1.2	V
t _{rr}	Diode Reverse Recovery Time	I _F = 15.3 A,		32		nS
Q _{rr}	Diode Reverse Recovery Charge	d _{iF} /d _t = 100 A/μs		39		nC

Notes:

1. R_{8JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{8JC} is guaranteed by design while R_{8CA} is determined by the user's board design.

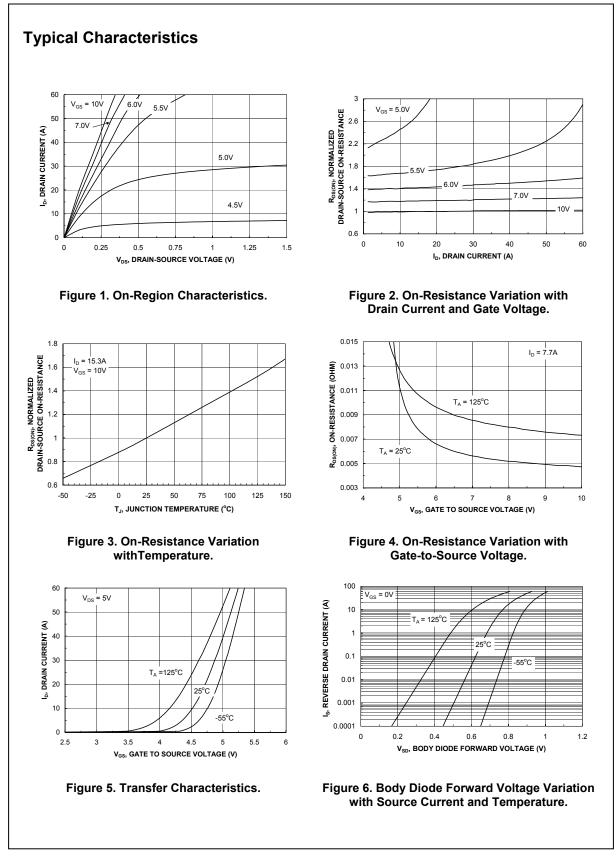


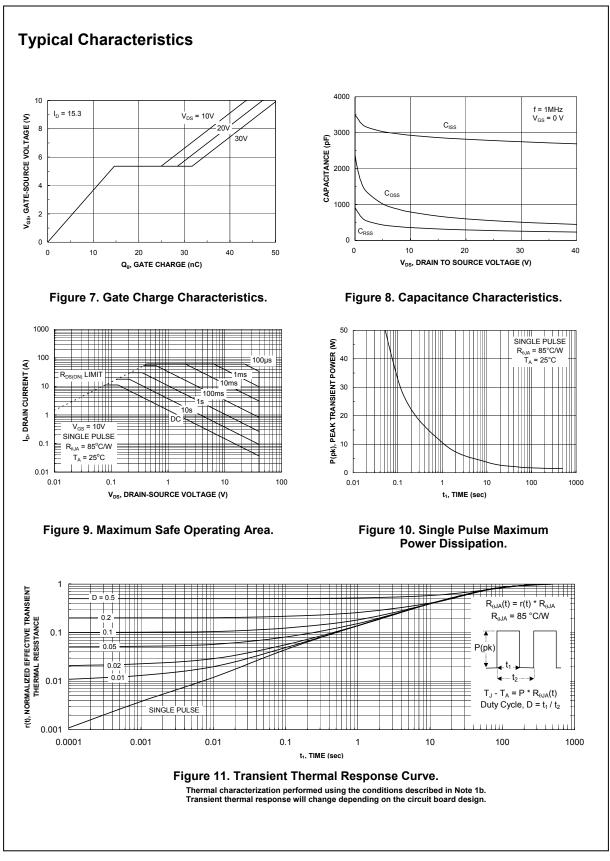
a) 40°C/W when mounted on a 1in² pad of 2 oz copper



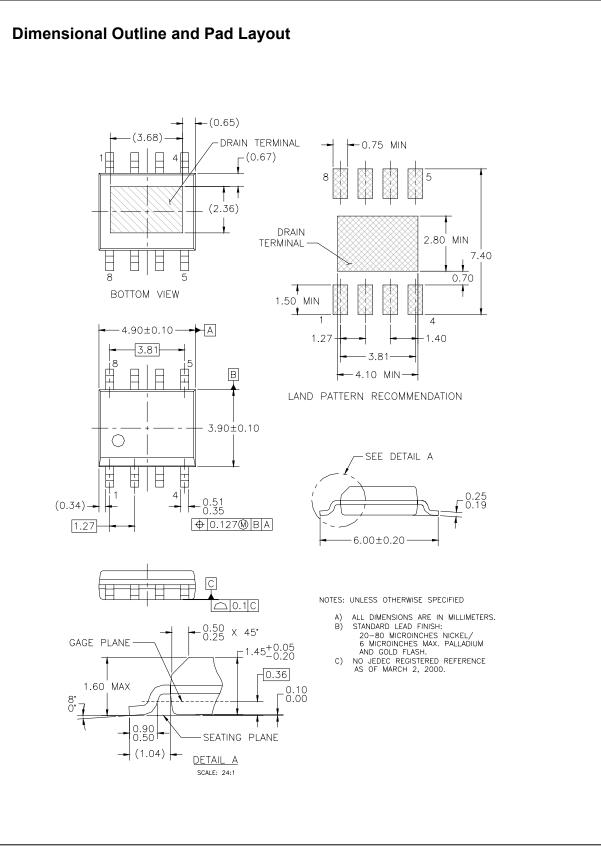
b) 85°C/W when mounted on a minimum pad of 2 oz copper

Scale 1 : 1 on letter size pape 2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0





FDS4070N3 Rev B2 (W)



FDS4070N3 Rev B2 (W)

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